

FDMS8560S

N-Channel PowerTrench® SyncFET™

25 V, 70 A, 1.8 mΩ

Features

- Max $r_{DS(on)}$ = 1.8 mΩ at $V_{GS} = 10$ V, $I_D = 30$ A
- Max $r_{DS(on)}$ = 2.1 mΩ at $V_{GS} = 4.5$ V, $I_D = 28$ A
- High performance technology for extremely low $r_{DS(on)}$
- SyncFET™ Schottky Body Diode
- RoHS Compliant

General Description

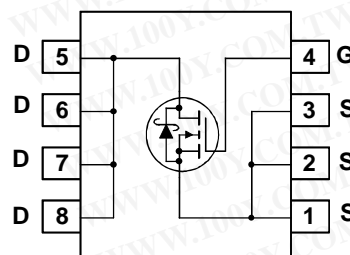
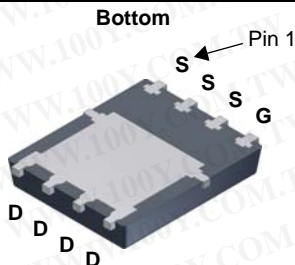
This N-Channel SyncFET™ is produced using Fairchild Semiconductor's advanced PowerTrench® process. Advancements in both silicon and package technologies have been combined to offer the lowest $r_{DS(on)}$ while maintaining excellent switching performance by extremely low Junction-to-Ambient thermal resistance. This device has the added benefit of an efficient monolithic Schottky body diode.

Applications

- Synchronous Rectifier for DC/DC Converters
- Telecom Secondary Side Rectification
- High End Server/Workstation Vcore Low Side



Power 56



MOSFET Maximum Ratings $T_A = 25^\circ\text{C}$ unless otherwise noted

Symbol	Parameter	Ratings	Units
V_{DS}	Drain to Source Voltage	25	V
V_{GS}	Gate to Source Voltage	12	V
I_D	Drain Current -Continuous (Package limited) $T_C = 25^\circ\text{C}$	70	A
	-Continuous $T_A = 25^\circ\text{C}$ (Note 1a)	30	
	-Pulsed	150	
E_{AS}	Single Pulse Avalanche Energy (Note 3)	79	mJ
P_D	Power Dissipation $T_C = 25^\circ\text{C}$	65	W
	Power Dissipation $T_A = 25^\circ\text{C}$ (Note 1a)	2.5	
T_J, T_{STG}	Operating and Storage Junction Temperature Range	-55 to +150	$^\circ\text{C}$

Thermal Characteristics

$R_{\theta JC}$	Thermal Resistance, Junction to Case	$T_C = 25^\circ\text{C}$	1.9	$^\circ\text{C/W}$
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient	$T_A = 25^\circ\text{C}$ (Note 1a)	50	

Package Marking and Ordering Information

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
050D	FDMS8560S	Power 56	13"	12 mm	3000 units

勝特力材料 886-3-5753170
勝特力电子(上海) 86-21-34970699
勝特力电子(深圳) 86-755-83298787
[Http://www.100y.com.tw](http://www.100y.com.tw)

Electrical Characteristics $T_J = 25^\circ\text{C}$ unless otherwise noted

Symbol	Parameter	Test Conditions	Min	Typ	Max	Units
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Off Characteristics

BV_{DSS}	Drain to Source Breakdown Voltage	$I_D = 1\text{ mA}$, $V_{GS} = 0\text{ V}$	25			V
$\frac{\Delta BV_{DSS}}{\Delta T_J}$	Breakdown Voltage Temperature Coefficient	$I_D = 10\text{ mA}$, referenced to 25°C		20		mV/ $^\circ\text{C}$
I_{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = 20\text{ V}$, $V_{GS} = 0\text{ V}$			500	μA
I_{GSS}	Gate to Source Leakage Current	$V_{GS} = +12\text{ V/-8 V}$, $V_{DS} = 0\text{ V}$			± 100	nA

On Characteristics

$V_{GS(th)}$	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}$, $I_D = 1\text{ mA}$	1.1	1.4	2.2	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate to Source Threshold Voltage Temperature Coefficient	$I_D = 10\text{ mA}$, referenced to 25°C		-3		mV/ $^\circ\text{C}$
$r_{DS(on)}$	Static Drain to Source On Resistance	$V_{GS} = 10\text{ V}$, $I_D = 30\text{ A}$		1.4	1.8	m Ω
		$V_{GS} = 4.5\text{ V}$, $I_D = 28\text{ A}$		1.6	2.1	
		$V_{GS} = 10\text{ V}$, $I_D = 30\text{ A}$, $T_J = 125^\circ\text{C}$		2.1	2.8	
g_{FS}	Forward Transconductance	$V_{DS} = 5\text{ V}$, $I_D = 30\text{ A}$		304		S

Dynamic Characteristics

C_{iss}	Input Capacitance	$V_{DS} = 13\text{ V}$, $V_{GS} = 0\text{ V}$, $f = 1\text{ MHz}$		4350		pF
C_{oss}	Output Capacitance			1270		pF
C_{rss}	Reverse Transfer Capacitance			138		pF
R_g	Gate Resistance			0.8		Ω

Switching Characteristics

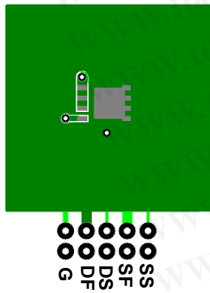
$t_{d(on)}$	Turn-On Delay Time	$V_{DD} = 13\text{ V}$, $I_D = 30\text{ A}$, $V_{GS} = 10\text{ V}$, $R_{GEN} = 6\text{ m}\Omega$		13		ns
t_r	Rise Time			6		ns
$t_{d(off)}$	Turn-Off Delay Time			45		ns
t_f	Fall Time			5		ns
Q_g	Total Gate Charge		$V_{GS} = 0\text{ V to } 10\text{ V}$	68		nC
Q_g	Total Gate Charge	$V_{DD} = 13\text{ V}$, $I_D = 30\text{ A}$	$V_{GS} = 0\text{ V to } 4.5\text{ V}$	32		nC
Q_{gs}	Gate to Source Gate Charge			8.2		nC
Q_{gd}	Gate to Drain "Miller" Charge			9.6		nC

Drain-Source Diode Characteristics

V_{SD}	Source to Drain Diode Forward Voltage	$V_{GS} = 0\text{ V}$, $I_S = 2\text{ A}$ (Note 2)		0.6	0.8	V
		$V_{GS} = 0\text{ V}$, $I_S = 30\text{ A}$ (Note 2)		0.8	1.2	
t_{rr}	Reverse Recovery Time	$I_F = 30\text{ A}$, $di/dt = 300\text{ A}/\mu\text{s}$		32		ns
Q_{rr}	Reverse Recovery Charge			41		nC

NOTES:

1. $R_{\theta JA}$ is determined with the device mounted on a FR-4 board using a specified pad of 2 oz copper as shown below. $R_{\theta JC}$ is guaranteed by design while $R_{\theta CA}$ is determined by the user's board design.



a) 50°C/W when mounted on a 1 in^2 pad of 2 oz copper



b) 125°C/W when mounted on a minimum pad of 2 oz copper.

2. Pulse Test: Pulse Width $< 300\text{ }\mu\text{s}$, Duty cycle $< 2.0\%$.

3. E_{AS} of 79 mJ is based on starting $T_J = 25^\circ\text{C}$, $L = 2.5\text{ mH}$, $I_{AS} = 8\text{ A}$, $V_{DD} = 23\text{ V}$, $V_{GS} = 10\text{ V}$. 100% test at $L = 0.1\text{ mH}$, $I_{AS} = 33.7\text{ A}$.

Typical Characteristics $T_J = 25^\circ\text{C}$ unless otherwise noted

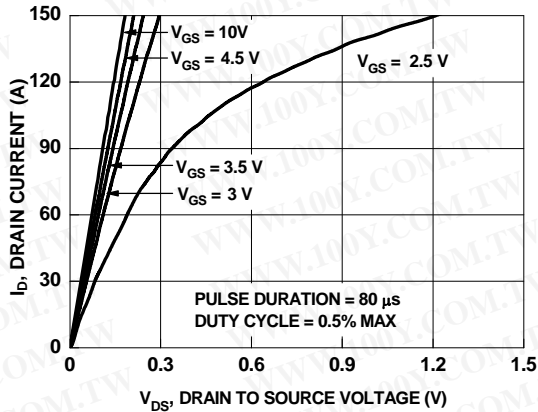


Figure 1. On Region Characteristics

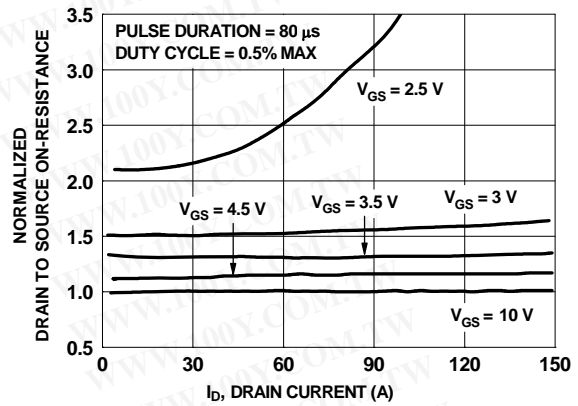


Figure 2. Normalized On-Resistance vs Drain Current and Gate Voltage

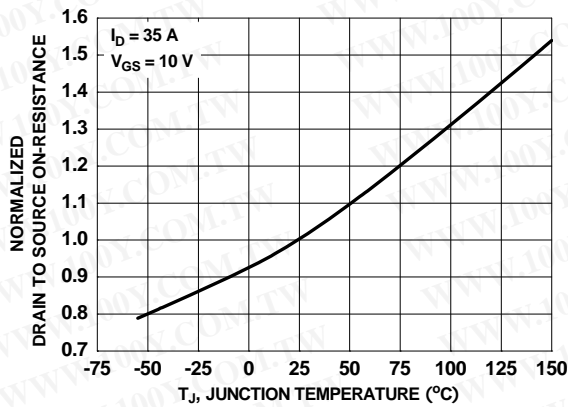


Figure 3. Normalized On Resistance vs Junction Temperature

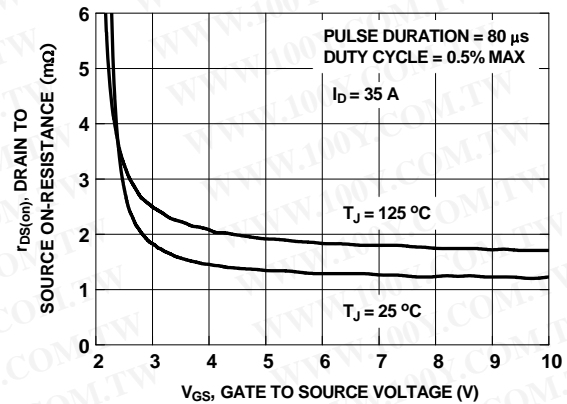


Figure 4. On-Resistance vs Gate to Source Voltage

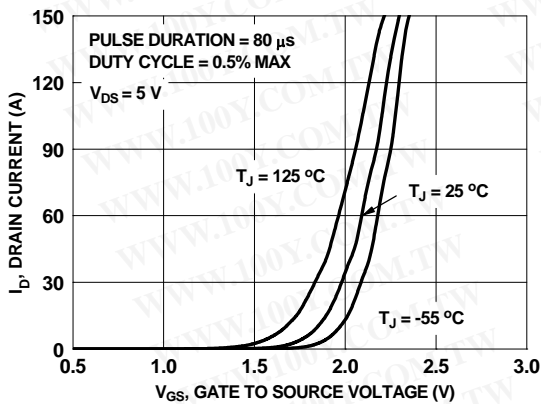


Figure 5. Transfer Characteristics

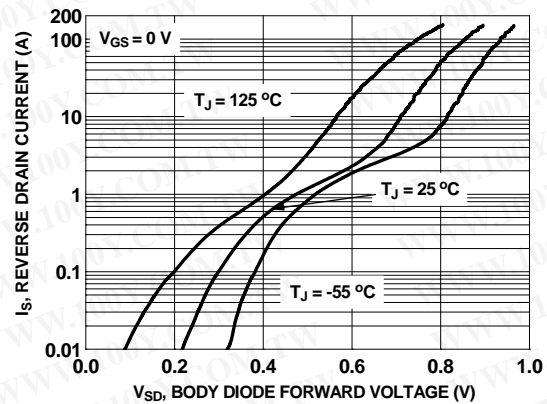


Figure 6. Source to Drain Diode Forward Voltage vs Source Current

Typical Characteristics $T_J = 25^\circ\text{C}$ unless otherwise noted

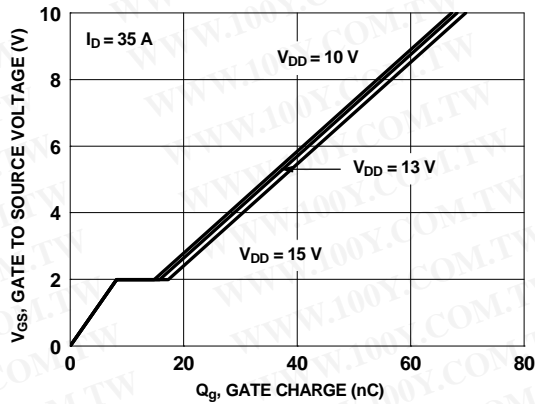


Figure 7. Gate Charge Characteristics

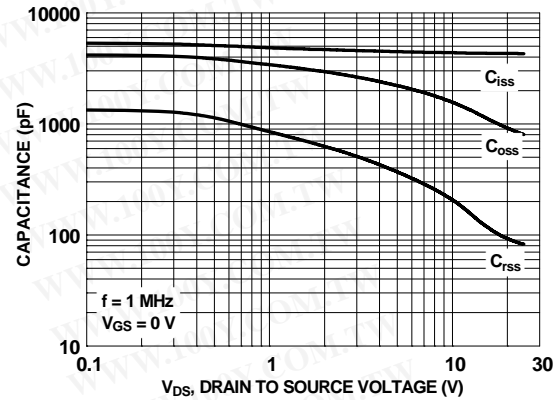


Figure 8. Capacitance vs Drain to Source Voltage

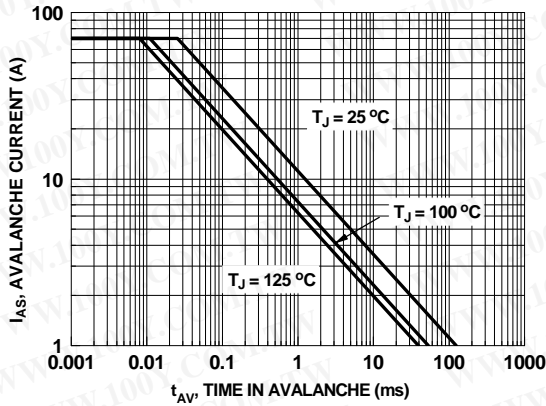


Figure 9. Unclamped Inductive Switching Capability

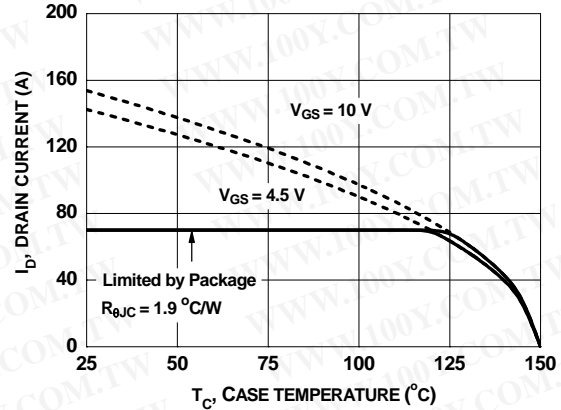


Figure 10. Maximum Continuous Drain Current vs Ambient Temperature

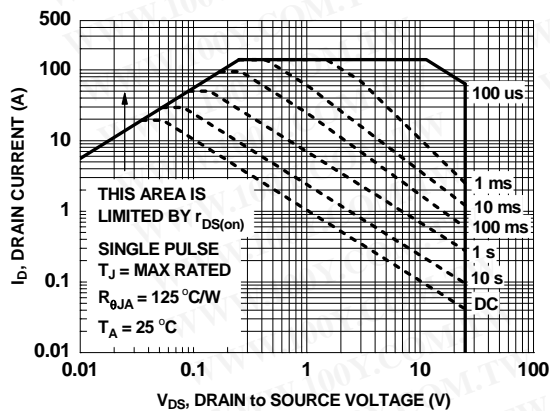


Figure 11. Forward Bias Safe Operating Area

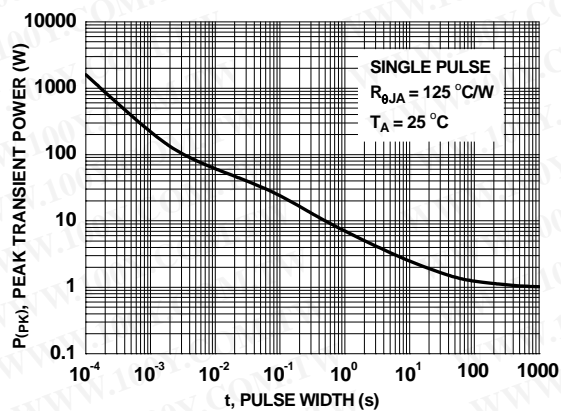
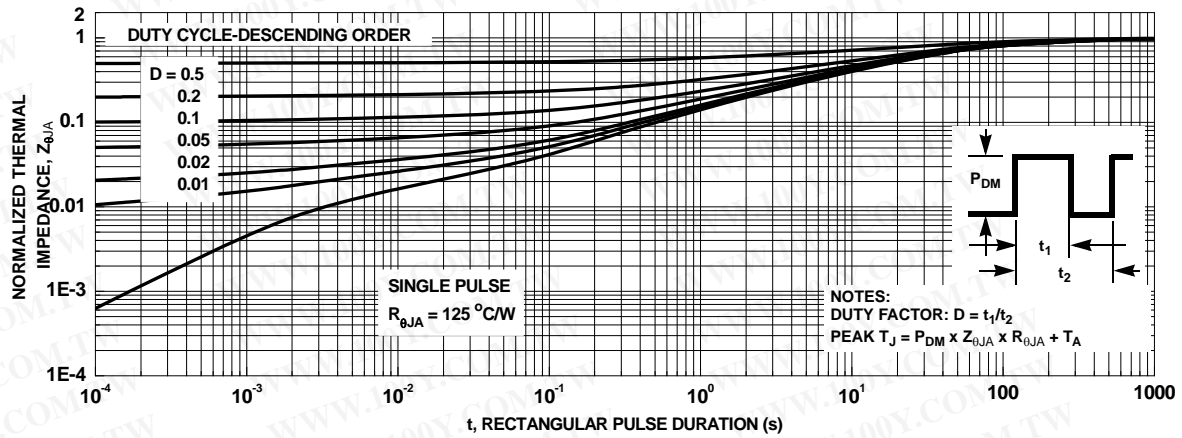


Figure 12. Single Pulse Maximum Power Dissipation

Typical Characteristics $T_J = 25^\circ\text{C}$ unless otherwise noted



Typical Characteristics (continued)

SyncFET™ Schottky body diode Characteristics

Fairchild's SyncFET™ process embeds a Schottky diode in parallel with PowerTrench MOSFET. This diode exhibits similar characteristics to a discrete external Schottky diode in parallel with a MOSFET. Figure 14 shows the reverse recovery characteristic of the FDMS8560S.

Schottky barrier diodes exhibit significant leakage at high temperature and high reverse voltage. This will increase the power in the device.

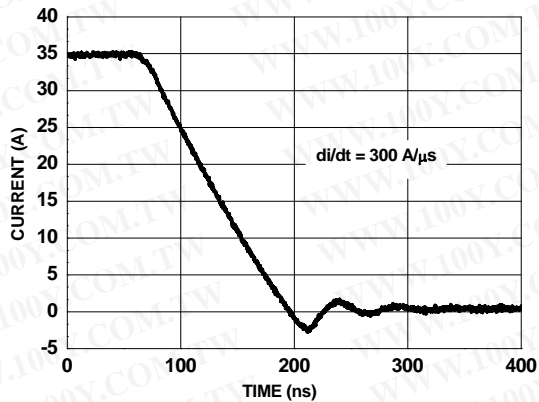


Figure 14. FDMS8560S SyncFET™ body diode reverse recovery characteristic

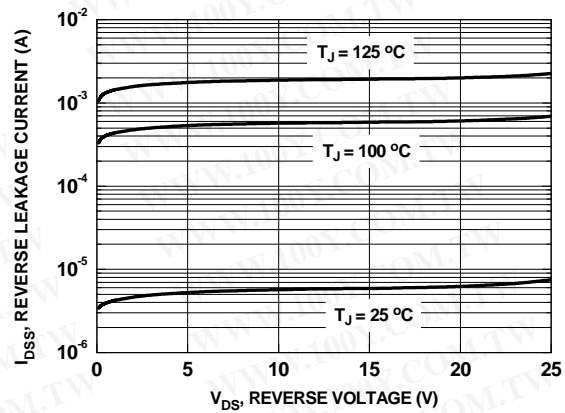
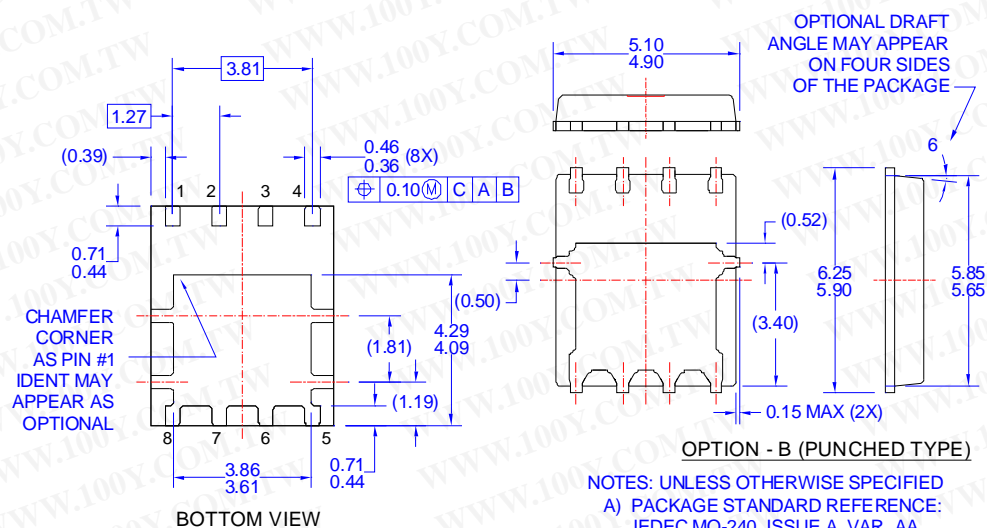
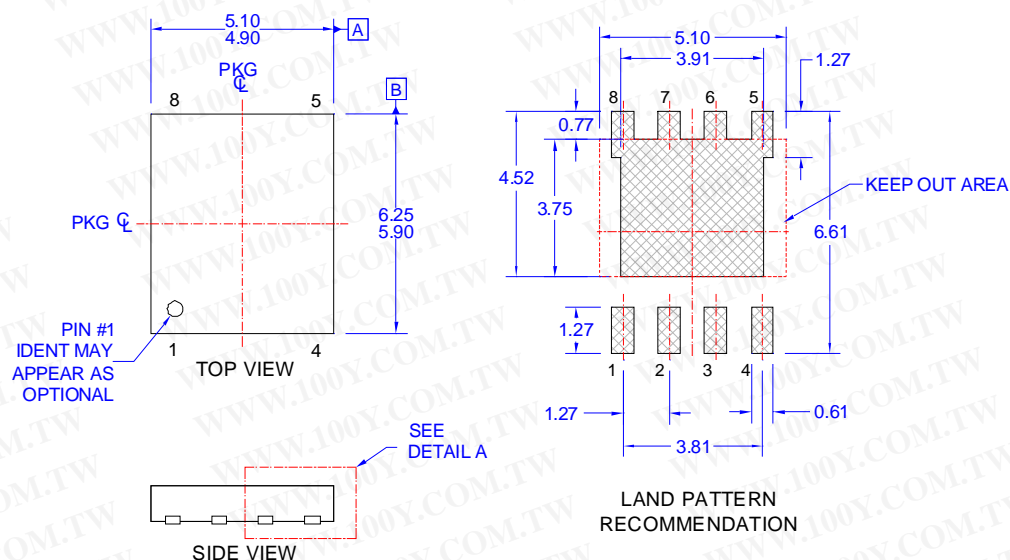


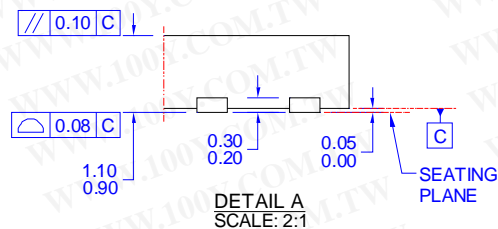
Figure 15. SyncFET™ body diode reverse leakage versus drain-source voltage

Dimensional Outline and Pad Layout



NOTES: UNLESS OTHERWISE SPECIFIED

- A) PACKAGE STANDARD REFERENCE:
JEDEC MO-240, ISSUE A, VAR. AA,
DATED OCTOBER 2002.
- B) ALL DIMENSIONS ARE IN MILLIMETERS.
- C) DIMENSIONS DO NOT INCLUDE BURRS
OR MOLD FLASH. MOLD FLASH OR
BURRS DOES NOT EXCEED 0.10MM.
- D) DIMENSIONING AND TOLERANCING PER
ASME Y14.5M-1994.
- E) IT IS RECOMMENDED TO HAVE NO TRACES
OR VIAS WITHIN THE KEEP OUT AREA.
- F) DRAWING FILE NAME:



OPTION - A (SAWN TYPE)

